

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination YOSHII ET AL.	
			Examiner Jason M. Perilla	Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0186912	08-2005	Nakao et al.	455/067.11
*	B	US-2004/0014482	01-2004	Kwak et al.	455/522
*	C	US-2003/0142658	07-2003	Ofuji et al.	370/349
*	D	US-2003/0081576	05-2003	Kim et al.	370/335
*	E	US-7,046,975	05-2006	Golitschek Edler Von Elbwart et al.	455/205
*	F	US-7,043,210	05-2006	Zhu et al.	455/102
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	Q					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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